PowerPhase, Dual N-Channel SO8FL

30 V, High Side 20 A / Low Side 24 A

Features

- Co-Packaged Power Stage Solution to Minimize Board Space
- Minimized Parasitic Inductances
- Optimized Devices to Reduce Power Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Converters
- System Voltage Rails
- Point of Load

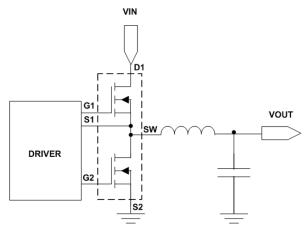


Figure 1. Typical Application Circuit

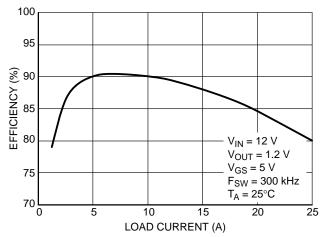


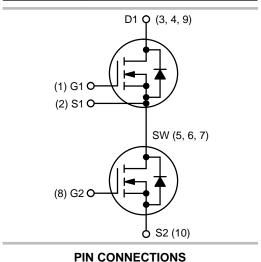
Figure 2. Typical Efficiency Performance **POWERPHASEGEVB Evaluation Board**



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
Q1 Top FET	5.4 mΩ @ 10 V	20.4
30 V	8.1 mΩ @ 4.5 V	20 A
Q2 Bottom	4.4 mΩ @ 10 V	24 A
FET 30 V	6.0 mΩ @ 4.5 V	24 A



5 SW 10 6 SW S2 D' 7 SW 8 G2 G1 (Bottom View)



DIAGRAM



MARKING

4C88N = Specific Device Code = Assembly Location Υ = Year

W = Work Week = Lot Traceability

ORDERING INFORMATION

See detailed ordering and shipping information on page 10 of this data sheet.

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter		Symbol	Value	Unit		
Drain-to-Source Voltage	Q1	V _{DSS}	30	V		
Drain-to-Source Voltage	Q2					
Gate-to-Source Voltage	Q1	V _{GS}	±20	V		
Gate-to-Source Voltage			Q2			
Continuous Drain Current R _{0JA} (Note 1)		T _A = 25°C	Q1	I _D	15.4	
		T _A = 85°C			11.1	1 ,
		T _A = 25°C	Q2		18.7	A
		T _A = 85°C			13.5	
Power Dissipation		T _A = 25°C	Q1	P _D	1.89	W
RθJA (Note 1)			Q2			
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s (Note 1)}$		T _A = 25°C	Q1	I _D	21.0	
		T _A = 85°C			15.1	A
	Steady	$T_A = 25^{\circ}C$	Q2		25.4	
	State	$T_A = 85^{\circ}C$			18.3	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$		$T_A = 25^{\circ}C$	Q1	P_{D}	3.51	W
N _{BJA} ≥ 10 3 (Note 1)			Q2			
Continuous Drain Current $R_{\theta JA}$ (Note 2)		$T_A = 25^{\circ}C$	Q1	I_{D}	11.7	
N _{HJA} (Note 2)		$T_A = 85^{\circ}C$			8.5	A
		T _A = 25°C	Q2		14.2	
		$T_A = 85^{\circ}C$			10.3	
Power Dissipation R _{0.JA} (Note 2)		T _A = 25 °C	Q1	P_{D}	1.10	W
N _{HJA} (Note 2)			Q2			
Pulsed Drain Current		$T_A = 25^{\circ}C$ $t_p = 10 \mu s$	Q1	I _{DM}	160	Α
		τρ = 10 μ3	Q2		240	
Operating Junction and Storage Temperature			Q1	T_J , T_{STG}	-55 to +150	°C
	Q2					
Source Current (Body Diode)	Q1	IS	10	Α		
	Q2		10			
Drain to Source DV/DT	•	dV/dt	6	V/ns		
Single Pulse Drain–to–Source Avalanche Energy (T V_{DD} = 50 V, V_{GS} = 10 V, L = 0.1 mH, R_{G} = 25 Ω)	Q1	EAS	20	mJ		
— 00 v, v _{GS} = 10 v, L = 0.1 mm, n _G = 20 s ₂)	Q2	EAS	29			
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface—mounted on FR4 board using 1 sq—in pad, 2 oz Cu.

2. Surface—mounted on FR4 board using the minimum recommended pad size of 100 mm².

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	66.0	
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	113.7	°C/W
Junction–to–Ambient – (t \leq 10 s) (Note 3)	$R_{\theta JA}$	35.6	

- 3. Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
- 4. Surface–mounted on FR4 board using the minimum recommended pad size of 100 mm².

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	mbol Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	•	
Drain-to-Source Break-	Q1	M	$V_{GS} = 0 \text{ V, } I_{D} = 250 \mu\text{A}$		30			V
down Voltage	Q2	V _{(BR)DSS}	$V_{GS} = 0 V$,	I _D = 250 μA	30			
Drain-to-Source Break- down Voltage Temperature	Q1	V _{(BR)DSS}				18		mV /
Coefficient	Q2	V _{(BR)DSS} /T _J				17		°C
	Q1		$V_{GS} = 0 V,$	T _J = 25°C			1	
Zero Gate Voltage Drain		I _{DSS}	$V_{DS} = 24 \text{ V}$	T _J = 125°C			10	μΑ
Current	Q2	.033	$V_{GS} = 0 V$, $V_{DS} = 24 V$	T _J = 25°C			1	
Gate-to-Source Leakage	Q1		V _{GS} :	= 0 V,			100	
Current		I _{GSS}	$V_{DS} = \pm 20 \text{ V}$				100	nA
ON CHARACTERISTICS (Not	e 5)							
Gate Threshold Voltage	Q1	V	$V_{GS} = VDS$,		1.3		2.2	V
	Q2	$V_{GS(TH)}$ $I_D = 250 \mu A$		250 μA	1.3		2.2	
Negative Threshold Temper-	Q1	V _{GS(TH)} /				4.5		mV /
ature Coefficient	Q2	T _J ′				4.6		°C
	Q1	R _{DS(on)}	$V_{GS} = 10 \text{ V}$	I _D = 10 A		4.3	5.4	_
Drain-to-Source On Resist-			$V_{GS} = 4.5 \text{ V}$	I _D = 10 A		6.5	8.1	mΩ
ance	Q2	_	$V_{GS} = 10 \text{ V}$	I _D = 20 A		2.8	4.4	
			$V_{GS} = 4.5 \text{ V}$ $I_D = 20 \text{ A}$			4.0	6.0	
CAPACITANCES								
Input Capacitance	Q1	Cinn	C _{ISS}			1252		
при Сараскансе	Q2	OISS				1546		
Output Capacitance	Q1	C _{OSS} V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15		MHz Vpc = 15 V		610		pF
Calpat Capacitario	Q2	9055	VGS = 0 V, I = I IVII IZ, VDS = 13 V			841		
Reverse Capacitance	Q1	C _{RSS}				126		
1.010100 Oapaoltanoo	Q2	OKSS.				39		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Condition		Min	Тур	Max	Unit
CHARGES, CAPACITANCE	& GATE	RESISTANC	E				•	
T. 10 1 01	Q1					10.9		
Total Gate Charge	Q2	$Q_{G(TOT)}$				11		1
TI 1 110 1 01	Q1	_				1.2		
Threshold Gate Charge	Q2	Q _{G(TH)}	V 45V/V	45.77.1 40.4		1.6		
0-1-1-0	Q1	_	$V_{GS} = 4.5 \text{ V}, V_{DS}$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 10 \text{ A}$		3.4		nC
Gate-to-Source Charge	Q2	Q_GS				4.4		
Onto the Duning Observe	Q1	0				5.4		
Gate-to-Drain Charge	Q2	Q_GD				2.9		
T. 10 . 0	Q1			45.77.1 40.4		22.2		_
Total Gate Charge	Q2	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS}$	= 15 V; I _D = 10 A		24.2		nC
0	Q1	R_{G}	_			1.0		
Gate Resistance	Q2		I _A =	25°C		1.0		Ω
SWITCHING CHARACTERIS	STICS (No	te 6)					•	
	Q1					9.4		
Turn-On Delay Time	Q2	t _{d(ON)}						1
Rise Time -	Q1					19		
	Q2	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 15 \text{ A}, R_G = 3.0 \Omega$			4.8		
T 0" D T	Q1	,	$I_D = 15 A$,	$R_G = 3.0 \Omega$		16		ns
Turn-Off Delay Time	Q2	t _{d(OFF)}				19.3		
E-U.T.	Q1					4.6		
Fall Time	Q2	t _f				4.7		
SWITCHING CHARACTERIS	STICS (No	te 6)						
Turn On Dolov Time	Q1					6.8		
Turn-On Delay Time	Q2	t _{d(ON)}				7.5		
Diag Time	Q1					17		
Rise Time	Q2	t _r	V _{GS} = 10 V,	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$		2.7		ns
Town Off Dalay Trees	Q1		$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			20.6		
Turn-Off Delay Time	Q2	^t d(OFF)				24.8		
	Q1					2.64		
Fall Time	Fall Time Q2					2.88		
DRAIN-SOURCE DIODE CH	IARACTE	RISTICS						
			$V_{GS} = 0 \text{ V},$	$T_J = 25^{\circ}C$		0.82		
Famous and Malks	Q1	.,	$V_{GS} = 0 V,$ $I_{S} = 10 A$	T _J = 125°C		0.64] ,,
Forward Voltage	6.5	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.8		_
	Q2		$I_{S} = 10 \text{ A}$	T _J = 125°C		0.62		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

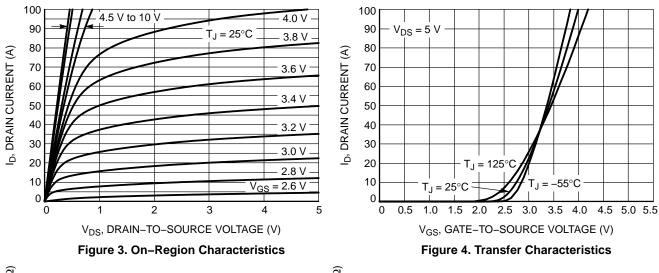
Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Condition	Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHA	RACTE	RISTICS						
Povorco Pocovory Timo	Q1	4			29			
Reverse Recovery Time	Q2	чRR	t _{RR}		16.7			
Chargo Timo	Q1	to	ta		14.2		ns	
Charge Time	Q2	та			19.5			
Discharge Time	Q1	4h	$V_{GS} = 0 \text{ V}, d_{IS}/d_t = 100 \text{ A/}\mu\text{s}, I_S = 10 \text{ A}$		15.0			
Discharge Time	Q2	tb	lb			36.2		
Dayaraa Dagayary Charga	Q1				18.1		20	
Reverse Recovery Charge	Q2	Q_{RR}			27.4		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$. 6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS - Q1



DRAIN-TO-SOURCE RESISTANCE (₺) DRAIN-TO-SOURCE RESISTANCE (₺) 0.026 0.009 0.024 0.022 $I_{D} = 20 \text{ A}$ 0.008 $T_J = 25^{\circ}C$ 0.020 V_{GS} = 4.5 V 0.018 0.007 0.016 0.014 0.006 0.012 0.005 0.010 V_{GS} = 10 V 0.008 0.006 0.004 R_{DS(on)}, I R_{DS(on)}, I 0.004 0.003 0.002 7 20 30 40 50 6 8 9 10 10 60 70 4 5 V_{GS}, GATE VOLTAGE (V) ID, DRAIN CURRENT (A)

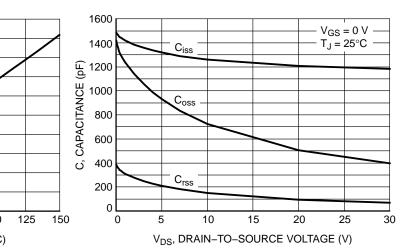
Figure 5. On-Resistance vs. Gate-to-Source Voltage

1.7

V_{GS} = 10 V

 $I_{D} = 20 \text{ A}$

0.7



-25 25 50 75 100 -50 T_J, JUNCTION TEMPERATURE (°C)

Figure 7. On-Resistance Variation with **Temperature**

Figure 8. Capacitance Variation

Figure 6. On-Resistance vs. Drain Current and **Gate Voltage**

TYPICAL CHARACTERISTICS - Q1

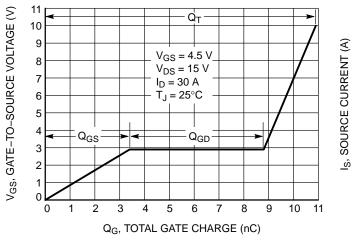


Figure 9. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

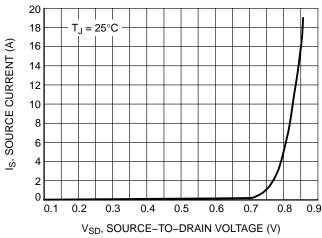


Figure 10. Diode Forward Voltage vs. Current

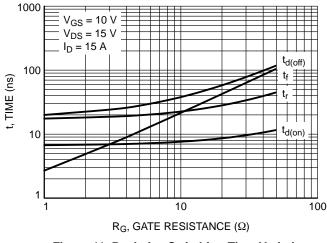


Figure 11. Resistive Switching Time Variation vs. Gate Resistance

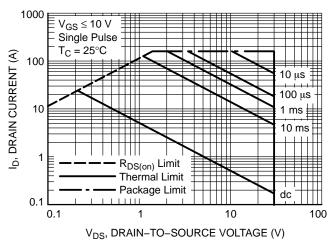


Figure 12. Maximum Rated Forward Biased Safe Operating Area

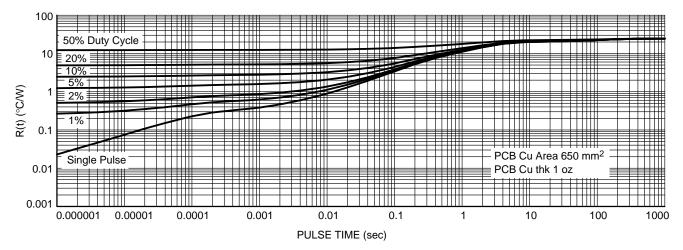


Figure 13. Thermal Characteristics

TYPICAL CHARACTERISTICS - Q2

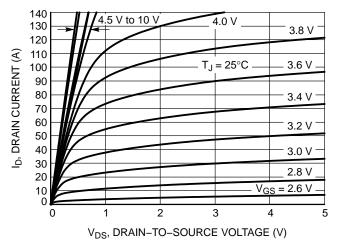


Figure 14. On-Region Characteristics

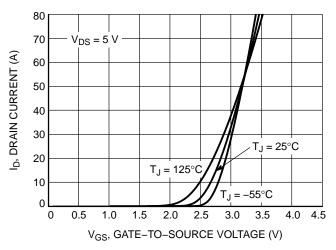


Figure 15. Transfer Characteristics

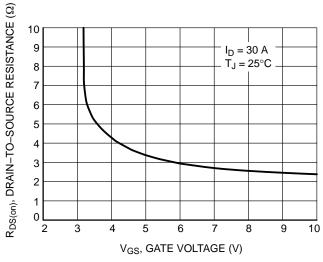


Figure 16. On-Resistance vs. Gate-to-Source Voltage

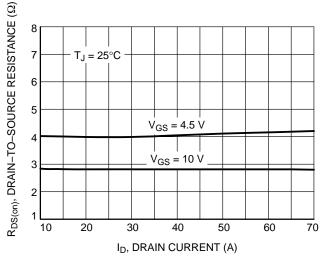


Figure 17. On-Resistance vs. Drain Current and Gate Voltage

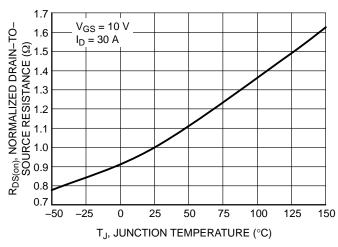


Figure 18. On–Resistance Variation with Temperature

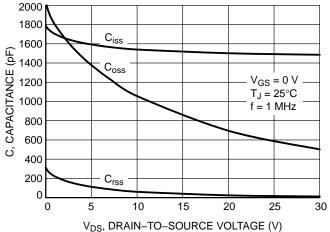


Figure 19. Capacitance Variation

TYPICAL CHARACTERISTICS - Q2

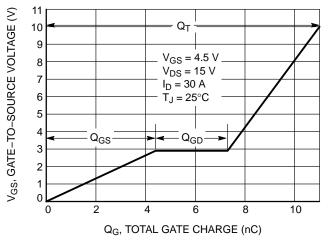


Figure 20. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

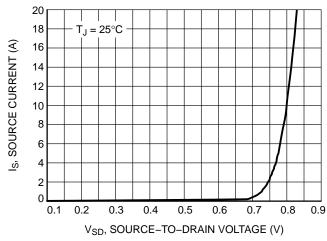


Figure 21. Diode Forward Voltage vs. Current

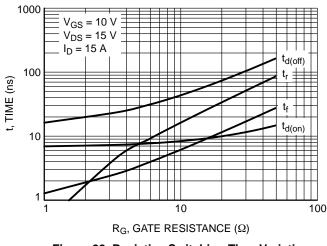


Figure 22. Resistive Switching Time Variation vs. Gate Resistance

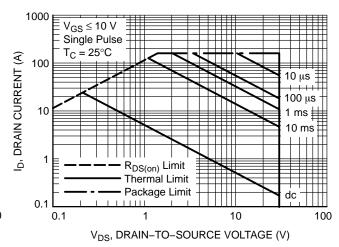


Figure 23. Maximum Rated Forward Biased Safe Operating Area

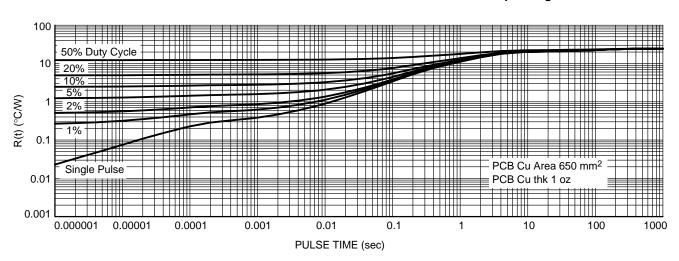


Figure 24. Thermal Characteristics

ORDERING INFORMATION

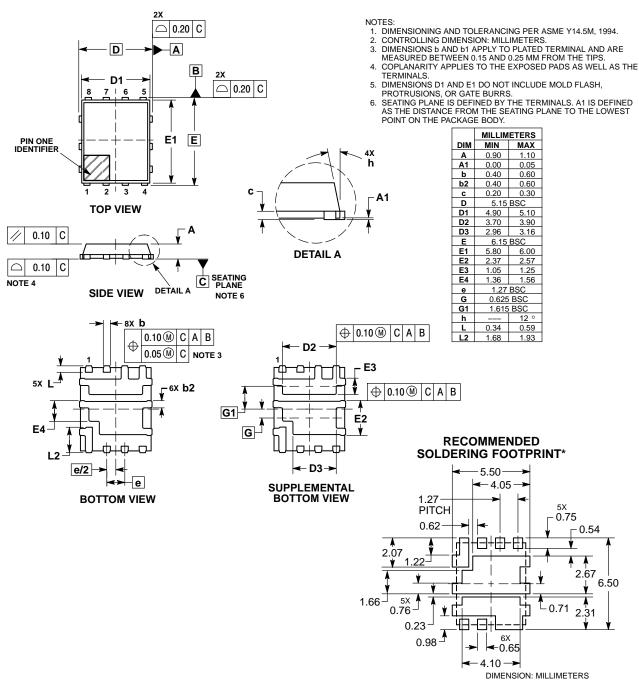
Device	Package	Shipping [†]
NTMFD4C88NT1G	DFN8 (Pb-Free)	1500 / Tape & Reel
NTMFD4C88NT3G	DFN8 (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

DFN8 5x6, 1.27P PowerPhase FET

CASE 506CR ISSUE C



^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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